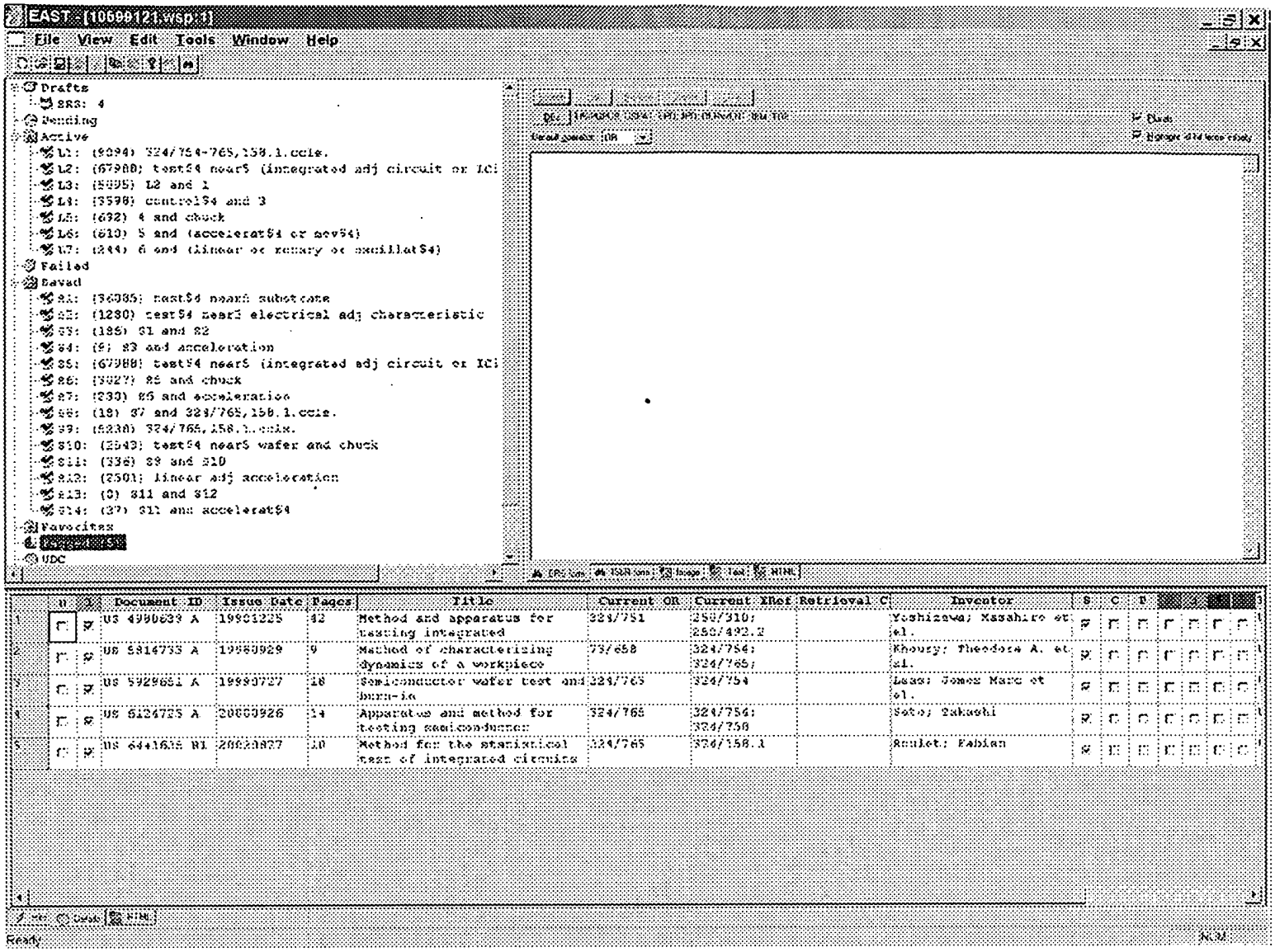

	D	S	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval C	Inventor	S	C	D
1		☑	US 4980639 A	19901225	42	Method and apparatus for testing integrated	324/751	250/310; 250/492.2		Yoshizawa; Masahiro et al.	☑	☐	☐
2		☑	US 5814733 A	19980929	9	Method of characterising dynamics of a workpiece	73/658	324/754; 324/765;		Khoury; Theodore A. et al.	☑	☐	☐
3		☑	US 5929651 A	19990727	18	Semiconductor wafer test and burn-in	324/765	324/754		Leas; James Marc et al.	☑	☐	☐
4		☑	US 6124725 A	20000926	14	Apparatus and method for testing semiconductor	324/765	324/754; 324/750		Sato; Takashi	☑	☐	☐
5		☑	US 6441635 B1	20020827	10	Method for the statistical test of integrated circuits	324/765	326/158.1		Amulet; Fabian	☑	☐	☐

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